IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application of

David Keith BOWEN et al.

Application No.: 10/004,785

Filed: December 7, 2001

For: X-RAY TOPOGRAPHIC SYSTEM

JUL 1 1 2003 9

Group Art Unit: 2882

Examiner: Irakli Kiknadze

Confirmation No.: 7963

INFORMATION DISCLOSURE STATEMENT TRANSMITTAL LETTER

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Enclosed is an Information Disclosure Statement and accompanying form PTO-1449 for the above-identified patent application.

- [] No additional fee for submission of an IDS is required.
- [] The fee of \$180.00 (1806) as set forth in 37 C.F.R. § 1.17(p) is also enclosed.
- [X] A statement under 37 C.F.R. § 1.97(e) is also enclosed.
- A statement under 37 C.F.R. § 1.97(e), and the fee of \$180.00 (1806) as set forth in 37 C.F.R. § 1.17(p) are also enclosed.
- [] Charge \$_____ to Deposit Account No. 02-4800 for the fee due.
- [] A check in the amount of \$_____ is enclosed for the fee due.

The Director is hereby authorized to charge any appropriate fees under 37 C.F.R. §§ 1.16, 1.17 and 1.21 that may be required by this paper, and to credit any overpayment, to Deposit Account No. 02-4800. This paper is submitted in duplicate.

Respectfully submitted,

BURNS, DOANE, SWECKER & MATHIS, L.L.P.

Date: <u>July 11, 2003</u>

By: James A. LaBarre

Registration No. 28,632

P.O. Box 1404 Alexandria, Virginia 22313-1404 (703) 836-6620

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Commissioner for Patents	
P.O. Box 1450	温图
Alexandria, VA 22313-1450	12 E RO
Sir:	OM

SECOND INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with the duty of disclosure as set forth in 37 C.F.R. § 1.56, Applicants hereby submits the following information in conformance with 37 C.F.R. §§ 1.97 and 1.98. Pursuant to 37 C.F.R. § 1.98, a copy of each of the documents cited is enclosed.

Submitted herewith are copies of documents cited in an International Search Report dated April 16, 2003, for corresponding PCT application PCT/GB02/05510. A copy of the Search Report is also being submitted herewith.

I, the undersigned, hereby state that each item of information contained in this Information Disclosure Statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement.

To assist the Examiner, the documents are listed on the attached form PTO-1449. It is respectfully requested that an Examiner-initialed copy of this form be returned to the undersigned.

Date: July 11, 2003

Respectfully submitted,

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Substitute for forms 1449A/PTO & 1449B/PTO	ATTORNEY'S DKT NO. 032516-002	APPLICATION NO. 10/004,785
SECOND INFORMATION DISCLOSURE	APPLICANT David Keith BOWEN et al.	
STATEMENT BY APPLICANT	FILING DATE December 7, 2001	GROUP 2882

TRAUENARM			J.S. PATENT DOCUMENTS	
Examiner Initials	Document Number	Kind Code (if known)	Name of Patentee or Applicant of Cited Document	Issue/Publication Date (MM-DD-YYYY)
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	4,351,063		Dineen et al.	09-21-1982
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Examiner Initials	Document Number	Kind Code (if known)	Country	Date of Publication (MM-DD-YYYY)	Translat Yes	ion No
	03-75548		Japan	03-29-1991	X	Π
	DE 196 24 094		Germany	06-19-1997	Abstract	Г
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	NON PATENT LITERATURE DOCUMENTS
Examiner Initials	Include name of author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
	G.J. PRICE et al., X-ray Focusing with Wolter Microchannel Plate Optics, Nuclear Instruments and Methods in Physics Research, 2002, pp.276-289, Vol. A 490, Elsevier Science B.V., Amsterdam, Holland

xaminer	Date
ignature	Considered

EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.03